

Search Notes



Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375	316	12/30/05	EH
↑	326	↑	↑
	327		
	328		
	340		
	341		
	344		
375	345	12/30/05	EH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
2151	12/30/05	C3